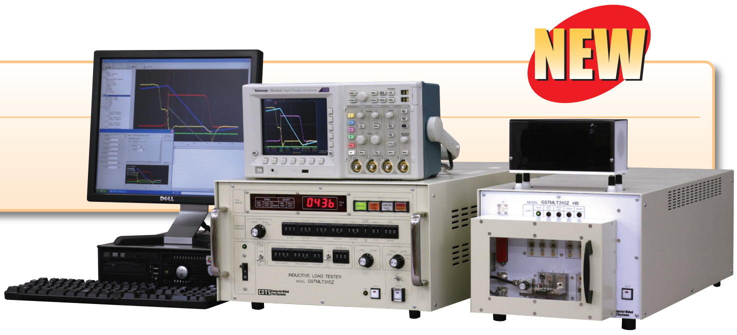
MOS-FET DIODE

INDUCTIVE LOAD TESTER L負荷テスター

GSTMLT310Z 300V 100A

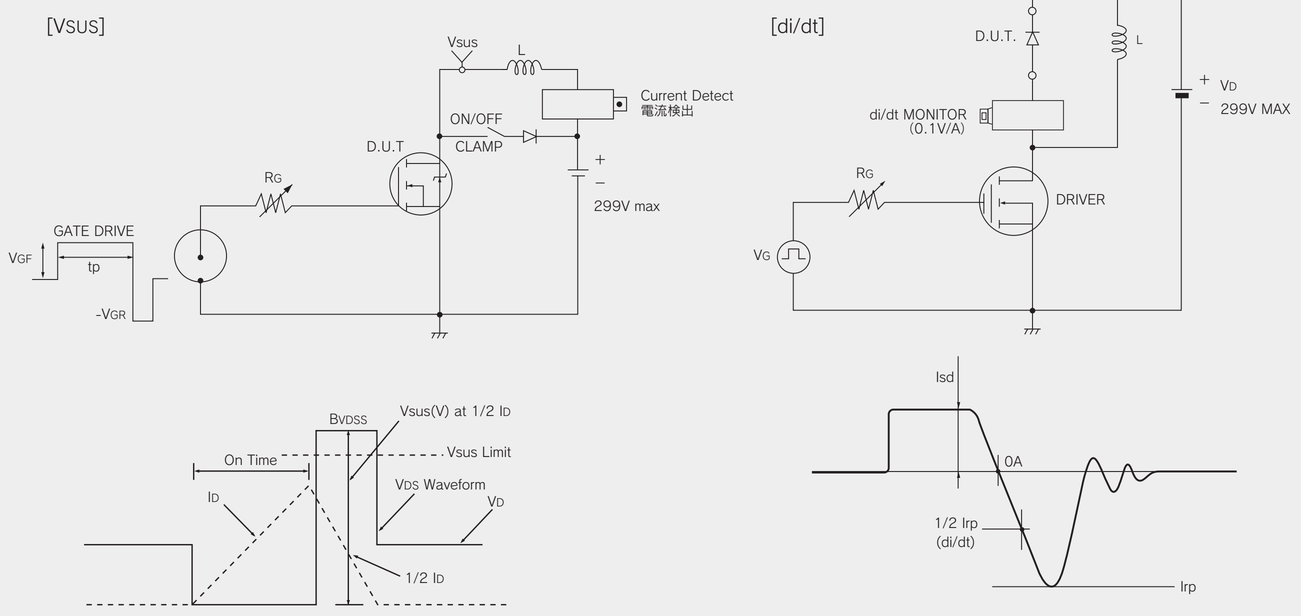
NEW



●GSTMLT310Z integrates di/dt measurement and inductive load measurement in one system. Measurement is carried out with the exclusive measurement terminal to consider waveform characteristics.

●di/dt測定とL負荷測定を一つのシステムに集約しました。波形特性を重視するため測定部はそれぞれ専用の測定端子にセットし測定を行います。

Fundamental Test Circuit



MODEL	GSTMLT310Z	
SETTING RANGE	[V_{SUS}]	[di/dt]
V_D	1V～299V	10V～299V
I_D	0.5A～99.9A[There are both Time and ID mode][Time/IDの両モードあり]	0.5A～99.9A
V_{GF}/V_{GR}	±0.0V～30.0V	±0.0V～30.0V
Rg	0.1Ω～99.9Ω	0.1Ω～99.9Ω
Clamp	on/off	—
REPEAT	1～19	1～19
V_{SUS} Limit	0V～999V	—
On Time	1μs～999μs	—
Time-1	—	000.1μs～999.9μs
Time-2	—	000.1μs～999.9μs
Time-3	—	1μs～99μs
JUDGE		
PRE-FAIL	SHORT : I_D current has reached 1/5 of the set value even when V_{GF} is off. SHORT : V_{GF} OFFでもI_D電流が規定の1/5以上流れている場合 OPEN : I_D current has not reached 1/5 of the set value even when V_{GF} is on. OPEN : V_{GF} ONでもI_D電流が規定の1/5以下の場合 I_D ERROR : I_D current has not reached set value in 1ms after V_{GF} is on. I_D ERROR : V_{GF} ON後1msでI_D電流値に達しなかった場合	PRE/POST CHECK OPEN : (V_{SD}(V_F)>3V) SHORT : (V_{DSS}(V_R)<V_D Setting×80%) DRIVER CHECK OPEN : (V_{DS}(VSAT)>V_D Setting×20%) SHORT : (V_{DSS}<V_D Setting×80%)
POST-FAIL	SHORT : I_D current has reached 1/5 of the set value even when V_{GF} is off. SHORT : V_{GF} OFFでもI_D電流が規定の1/5以上流れている場合 OPEN : I_D current has not reached 1/5 of the set value even when V_{GF} is on. OPEN : V_{GF} ONでもI_D電流が規定の1/5以下の場合	
LIMIT-FAIL	V_{SUS} waveform has not reached to V_{SUS} Limit voltage at 1/2 I_D current. V_{SUS}波形時、1/2 I_D電流においてV_{SUS}波形がV_{SUS} Limit電圧未満の場合	
DIMENSIONS & WEIGHT		
MAIN UNIT	430(W)×700(D)×245(H)…45kg	
HEAD BOX	290(W)×650(D)×230(H)+Coil…30kg	